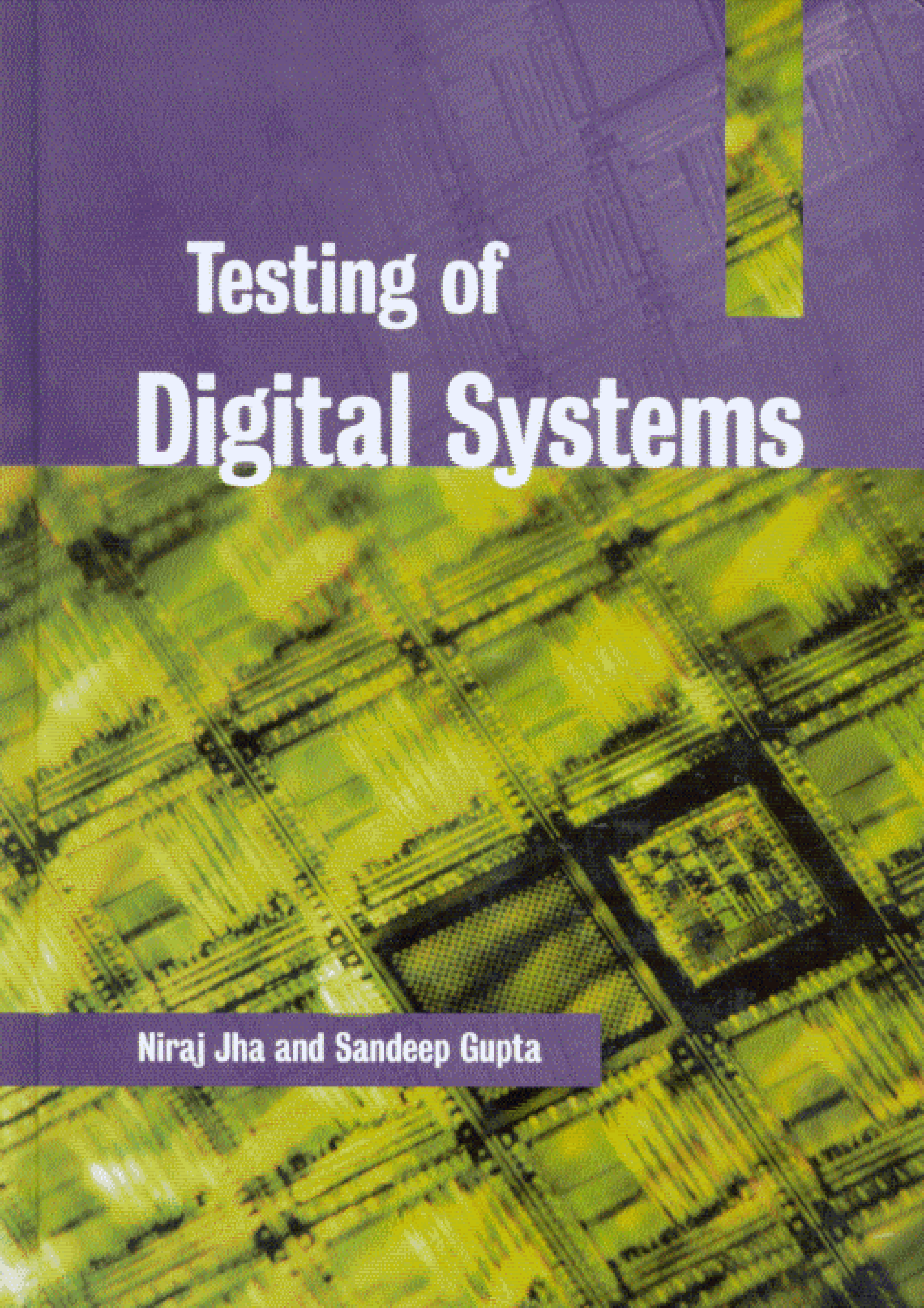

Testing of
Digital Systems

Niraj Jha and Sandeep Gupta

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